

<b>Notice of References Cited</b>	Application/Control No. 10/628,327	Applicant(s)/Patent Under Reexamination IIDA, TAKAYUKI	
	Examiner Nhan T. Tran	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0041056	11-2001	Tanaka et al.	348/232
*	B	US-2003/0214602	11-2003	Battles et al.	348/375
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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